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CLAIMS

What is claimed is:

- A process for creating an electrically isolated electrode 1. 1 on a sidewall of a cavity in a base, the process 2 comprising the steps of: 3
- etching one or more trenches in a backside of the base; 4 forming a layer of insulating material on one or more 5 sidewalls of one or more of the trenches; Ь forming a conductive layer on the layer of insulating material on one or more sidewalls of one or more of the trenches; and;
 - removing base material from a portion of the base bordered by the one or more trenches.
 - The process of claim 1, wherein the trenches are defined 2. underneath a flap.
 - The process of claim 1, wherein the trench etch stops on 3. an etch-stop layer.
 - The process of claim 1, wherein the conductive layer ŀ 4. completely fills the trench. 2
 - The process of claim 1, wherein a layer of conducting 5. ŀ material is also deposited on the backside of the base. 2
 - The process of claim 1, wherein the trench is formed using 6. ŀ an anisotropic etch. 2
 - The process of claim 1, wherein the base is a crystalline 7. L material. 2

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- 8. The process of claim 1 wherein the trench is etched such
 that an orientation of the sidewall is defined by a
 crystal orientation of the base material.
- 9. The process of claim 8, wherein the base is composed of crystalline silicon having a <110> crystal orientation.